

**Toshiba****INTEGRATED CIRCUIT****東芝****TECHNICAL DATA****TA7621P**TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT  
SILICON MONOLITHIC

## TV CHROMA PROCESSER

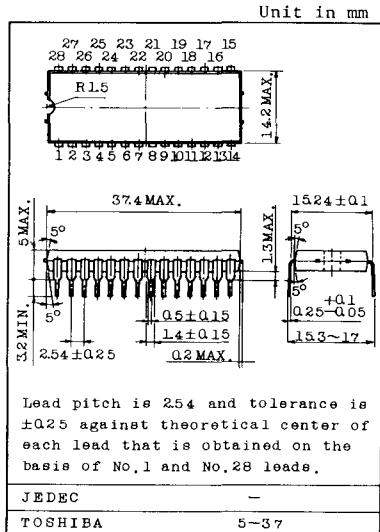
(FOR SECAM SYSTEM)

## FUNCTION

- . Chroma Amplifier
- . SECAM Switch
- . R-Y/B-Y Chroma Signal Limitter Amplifier
- . R-Y/B-Y Demodulator
- . H-Blanking Circuit
- . Killer and Ident Circuit
- . Burst Gate Circuit
- . Flip-Flop

## FEATURES

- . Having a main color signal processing function in one package.
- . Minimum number of external parts required.
- . A little harmonic frequency generation from R-Y/B-Y demodulator and killer/Ident detector.
- . Be able to select line or field IDENT system with external circuit.



Lead pitch is 2.54 and tolerance is  
 $\pm 0.025$  against theoretical center of  
 each lead that is obtained on the  
 basis of No.1 and No.28 leads.

JEDEC

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5-37

## MAXIMUM RATINGS (Ta=25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Supply Voltage		V <sub>CC</sub>	15	V
Signal Level at Input Pin		e <sub>in</sub>	5	V <sub>p-p</sub>
Chroma Amp. Output Current	DC	I <sub>O(DC)</sub>	7	mA
	AC	I <sub>O(AC)</sub>		
Pulse Input Voltage	Burst Gate	e <sub>p20</sub>	±6	V
	Flip-Flop	e <sub>p19</sub>	±5	V
Power Dissipation		P <sub>D</sub>	1.4	W
Operating Temperature		T <sub>opr</sub>	-20 ~ 65	°C
Storage Temperature		T <sub>stg</sub>	-55 ~ 150	°C



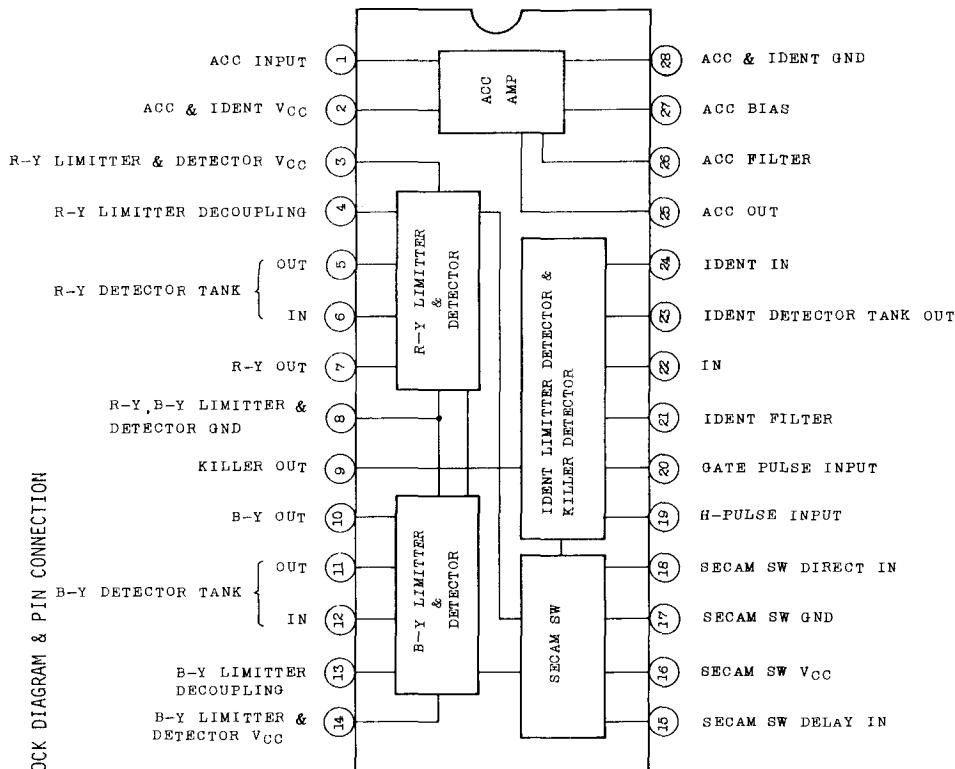
# INTEGRATED CIRCUIT



## TECHNICAL DATA

TA 7621 P

BLOCK DIAGRAM & PIN CONNECTION





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## TECHNICAL DATA

TA7621P

ELECTRICAL CHARACTERISTICS (Unless otherwise specified, V<sub>CC</sub>=12V, Ta=25°C)

CHARACTERISTIC	SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Supply Current	I <sub>CC</sub>	Fig.1	R <sub>L</sub> ACC=∞	33	50	67	mA
Power Dissipation	P <sub>D</sub>	Fig.1	R <sub>L</sub> ACC=∞	-	600	804	mW
Supply Current	Pin 2 I <sub>2</sub>	Fig.1	R <sub>L</sub> ACC=1kΩ	22	30	38	mA
	Pin 16 I <sub>16</sub>	Fig.1	-	5.2	7.6	10.0	mA
	Pin 3 I <sub>3</sub>	Fig.1	-	7.5	10.6	14.2	mA
	Pin 14 I <sub>14</sub>	Fig.1	-	7.5	10.6	14.2	mA
ACC Input DC Voltage	V <sub>1</sub>	Fig.1	-	1.5	1.9	2.3	V
ACC Output DC Voltage	V <sub>25</sub>	Fig.1	R <sub>L</sub> ACC=1kΩ	-	7.7	-	V
Output DC Voltage	R-Y V <sub>7</sub>	Fig.1	-	6.9	7.7	8.5	V
	B-Y V <sub>10</sub>	Fig.1	-	6.9	7.7	8.5	V
SECAM Switch Input DC Voltage	V <sub>15</sub> ,V <sub>18</sub>	Fig.1	-	1.7	2.2	2.7	V
Killer Output DC Voltage	ON V <sub>9(ON)</sub>	Fig.1	Note 1	-	1.0	2.0	V
	OFF V <sub>9(OFF)</sub>			11.5	12	-	V
ACC Amp. Output Saturation	e <sub>25S</sub>	Fig.2	f=4.5MHz RF <sub>in</sub> =200mV <sub>p-p</sub>	1.1	1.5	1.9	V <sub>p-p</sub>
Variation of ACC Amp. Output Saturation	Δe <sub>25</sub>	Fig.2	f=4.5MHz RF <sub>in</sub> =100 ~ 200V <sub>p-p</sub>	-	0	25	mV
Input Sensitivity of ACC AMP	e <sub>1L</sub>	Fig.2	f=4.5MHz 3dB Down e <sub>25S</sub>	-	12	25	mV <sub>p-p</sub>
Ident Amp. Output Saturation	e <sub>23S</sub>	Fig.2	f=4.5MHz RF <sub>in</sub> =1V <sub>p-p</sub>	0.9	1.3	-	V <sub>p-p</sub>
Variation of Ident Amp. Output Saturation	Δe <sub>23</sub>	Fig.2	f=4.5MHz RF <sub>in</sub> =0.5 ~ 1V <sub>p-p</sub>	-	0	25	mV <sub>p-p</sub>
Input Sensitivity of Ident Amp.	e <sub>24L</sub>	Fig.2	f=4.5MHz 3dB Down e <sub>23S</sub>	-	240	-	mV <sub>p-p</sub>
Center Frequency of Ident	f <sub>0(I)</sub>	Fig.4	Note 2	-	4,328	-	MHz
Bandwidth of Ident Detector	f <sub>D(I)</sub>	Fig.4	Note 3	-	45	100	kHz
Ident Detector Sensitivity	e <sub>0(I)</sub>	Fig.4	Note 4	-	1.0	-	V <sub>p-p</sub>
Killer Switch Threshold	V <sub>21(K)</sub>	Fig.4	Note 6	-	6.6	-	V
Ident Switch Threshold	V <sub>21(I)</sub>	Fig.4	Note 6	-	7.7	-	V
Ident Switch DC Voltage	V <sub>21</sub>	Fig.4	Note 7	-	6.9	-	V



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CHARACTERISTIC		SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Minimum Gate Pulse		Ident	V <sub>G</sub>	Fig.4 Note 8	2.0	-	-	V
		Blanking	V <sub>B</sub>	Fig.4 -	1.5	-	-	V
SECAM Switch		Output Saturation	V <sub>11S</sub> V <sub>5S</sub>	Fig.5 Note 9	1.0	1.6	-	V <sub>p-p</sub>
		Input Knee	V <sub>15L</sub> V <sub>18L</sub>	Fig.5 -	-	25	60	mV <sub>p-p</sub>
		Cross-talk	-	Fig.5 Note 10	-	-40	-36	dB
		Frequency Response	-	Fig.5 -	3.5	4.1	-	MHz
		Center Frequency	f <sub>0(R)</sub> f <sub>0(B)</sub>	Fig.6 RFin=200mV <sub>p-p</sub>	4.2	4.5	4.8	MHz
Color Detector	Sensitivity	R-Y	e <sub>0(R)</sub>	Fig.6 -	200	300	400	mV <sub>p-p</sub>
		B-Y	e <sub>0(B)</sub>					
	Voltage Sensitivity	R-Y	Δe <sub>0RV</sub>	Fig.6 V <sub>CC</sub> =11~13V	-	13	-	mV <sub>p-p</sub> /V
		B-Y	Δe <sub>0BV</sub>					
	Temperature Sensitivity	R-Y	Δe <sub>0RT</sub>	Fig.6 Ta=25±20°C	-	0	-	mV <sub>p-p</sub> /V
		B-Y	Δe <sub>0BT</sub>					
	Bandwidth	R-Y	-	Fig.6 -	1.1	1.4	-	MHz
		B-Y	-					
Frequency Response	R-Y	-	Fig.6 f <sub>0</sub> =4.5MHz	0.5	1.0	-	MHz	
	B-Y	-						
Output Voltage	R-Y	-	Fig.7 -	1.28	1.6	1.92	V <sub>p-p</sub>	
	B-Y	-		1.01	1.26	1.51		
Killer Residual Signal		-	Fig.6 Note 11	-	70	-	mV <sub>p-p</sub>	
Color Detector AMR		-	Fig.6 Note 12	39	50	-	dB	
Killer Threshold		-	Fig.7 Note 13	0.9	1.6	2.25	mV <sub>p-p</sub>	
Limitting Sensitivity of Color Detector		-	Fig.7 Note 14	-	2.8	6.0	mV <sub>p-p</sub>	
DC Offset at Evry 1H		-	Fig.7 Note 15	-	0	20	mV	
Cross-talk		-	Fig.7 Note 16	-30	-40	-	dB	

## TEST CIRCUIT

Fig. 1 DC TEST CIRCUIT

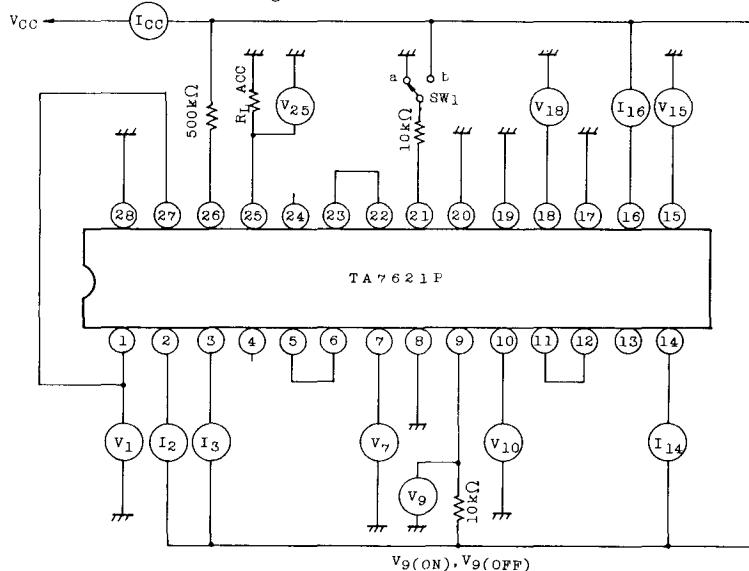
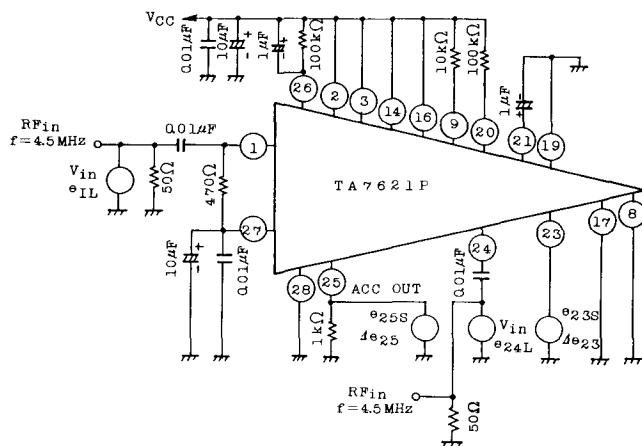


Fig. 2 ACC IDENT TEST CIRCUIT



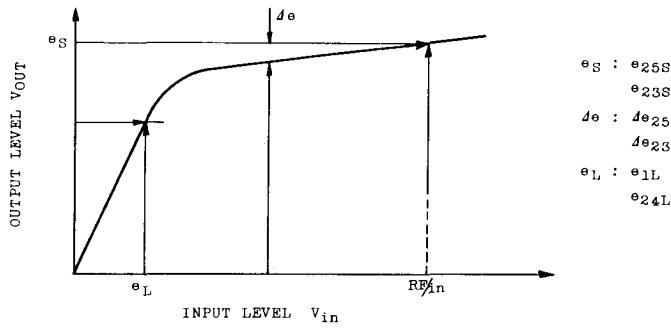


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## TECHNICAL DATA

Fig. 3 ACC AMP/IDENT AMP



## CHARACTERISTICS

Fig. 4 IDENT TEST CIRCUIT

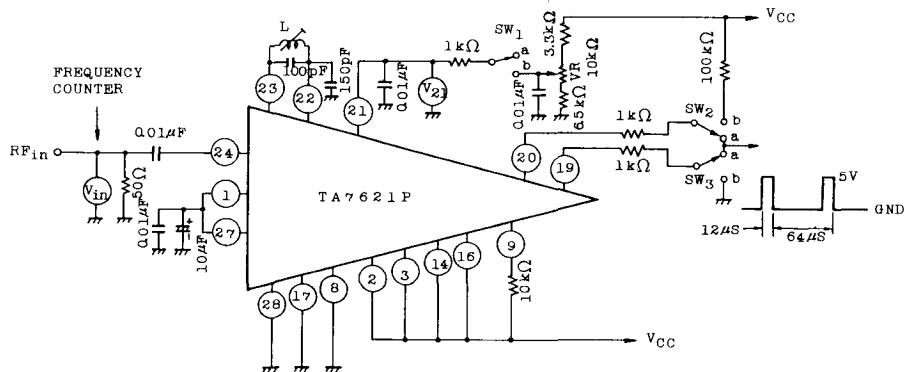


Fig. 5 SWITCH CIRCUIT

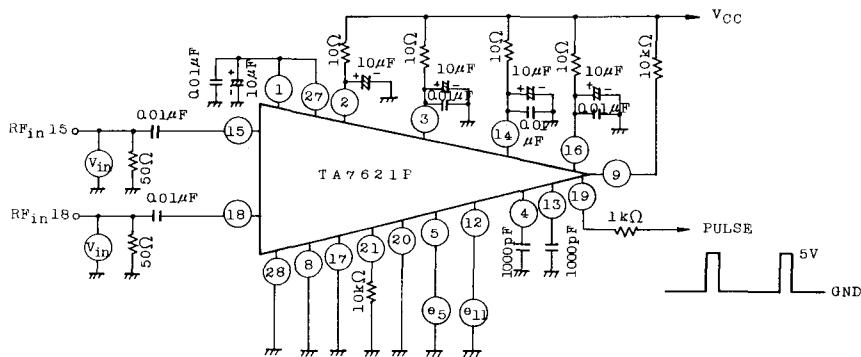
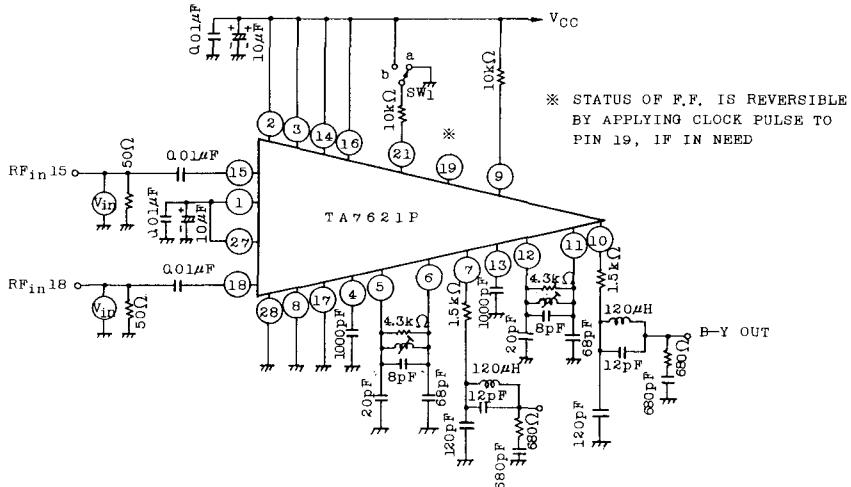


Fig. 6 DETECTOR TEST CIRCUIT



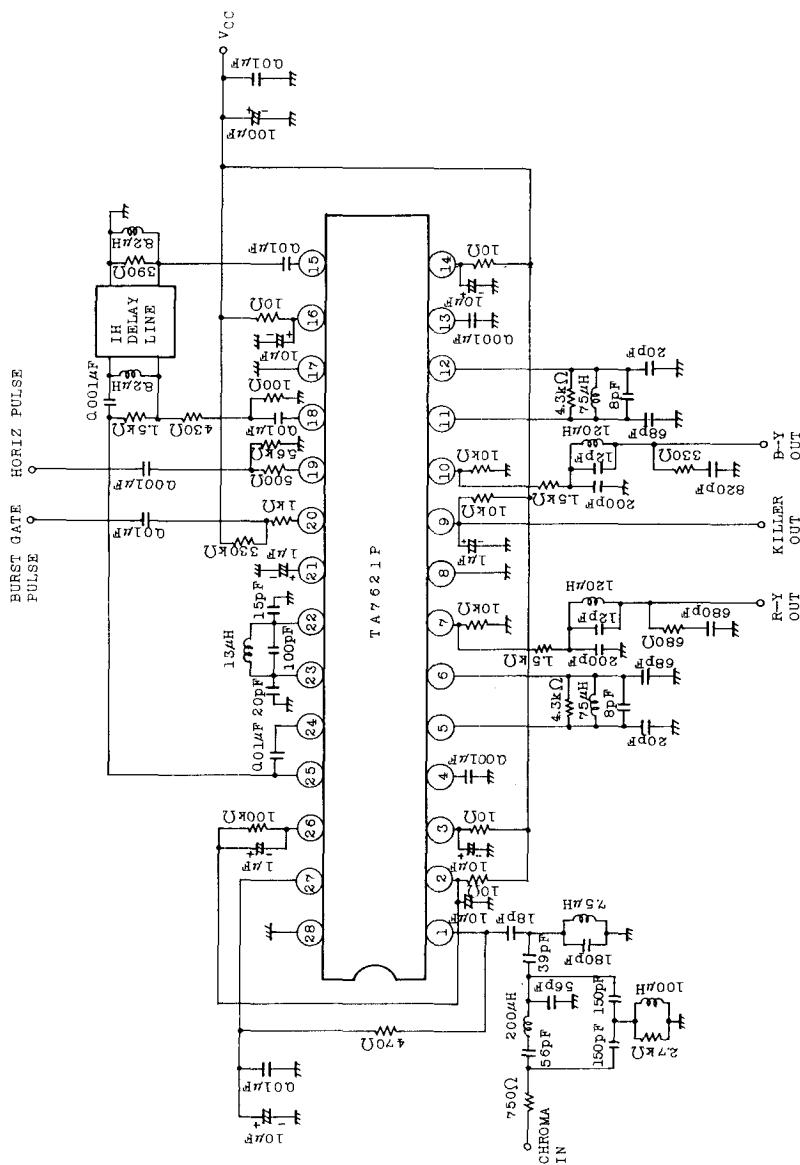


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T A 7 6 2 1 P

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Fig. 7 AC TEST CIRCUIT



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- NOTE 1 Killer Output DC Voltage  
Measure V<sub>9(0)</sub> with SW1 at position b, and V<sub>9(1)</sub> at position a.
- NOTE 2 Center Frequency of Ident (Fig.4)  
Measure pin 21 DC voltage E<sub>0</sub> with no signal and determine f<sub>0(I)</sub> as the frequency which make the pin 21 voltage same as E<sub>0</sub>.
- NOTE 3 Ident Detector Bandwidth (Fig.4)  
Set SW1 to position b, fix 10kΩ VR to the point where pin 21 voltage become same as E<sub>0</sub> measured in NOTE 2.  
Then, set SW1 and SW2 to position a and measure the f<sub>L</sub> which is the frequency to give 90% drop from E<sub>0</sub> to lowest pin 21 level, and f<sub>H</sub> 90% of the highest level from E<sub>0</sub>.  
Ident Bandwidth is given by f<sub>D(I)</sub>=|f<sub>H</sub>-f<sub>L</sub>|.
- NOTE 4 Ident Detector Sensitivity (Fig.4)  
With the same setting as NOTE 3, measure the AC output of pin 21 at center frequency.  
 $f_m=400\text{Hz}$ , Deviation=15kHz
- NOTE 5 Killer Switch Threshold (Fig.4)  
After setting SW1, SW2 and SW3 to position b, changing 10kΩ VR, measure pin 21 voltage which change the pin 9 output.
- NOTE 6 Ident Switch Threshold (Fig.4)  
Set SW1 to position b, measure the level of pin 21 which stop Flip-Flop.
- NOTE 7 Minimum Gate Pulse for Ident (Fig.4)  
Check the Ident gate pulse height which activates Ident detector.
- NOTE 8 Minimum Blanking Pulse Input Level (Fig.4)  
Check the blanking input threshold which activates the blanking action.
- NOTE 9 SECAM Switch Output Saturation (Fig.5)  
Applying input to pin 15 and pin 18 together, check the output at pin 11 and pin5.



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NOTE 10 SECAM Switch Cross-talk (Fig.5)

Ratio of peak to peak output at pin 11 with input from pin 15/pin 18  
(F.F. at same state).

NOTE 11 Killer Residual Signal (Fig.6)

Set SW1 to position b, and activate killer.

NOTE 12 Color Detector AMR (Fig.6)

FM 100kHz Dev.

AM 30% mod.

$f_m$  1kHz